Power MOSFET, N-Channel, 600 V, 2.0 Ω

Features

- Low ON Resistance
- Low Gate Charge
- ESD Diode-Protected Gate
- 100% Avalanche Tested
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

ABSOLUTE MAXIMUM RATINGS (T_C = 25°C unless otherwise noted)

Parameter	Symbol	NDF	NDD	Unit
Drain-to-Source Voltage	V _{DSS}	60	00	٧
Continuous Drain Current R _{θJC} (Note 1)	I _D	4.8	4.1	Α
Continuous Drain Current $R_{\theta JC}$, $T_A = 100^{\circ}C$ (Note 1)	I _D	3.0	2.6	Α
Pulsed Drain Current, V _{GS} @ 10V	I _{DM}	20	20	Α
Power Dissipation $R_{\theta JC}$	P_{D}	30	83	W
Gate-to-Source Voltage	V _{GS}	±3	30	٧
Single Pulse Avalanche Energy, I _D = 4.0	E _{AS}	120		mJ
ESD (HBM) (JESD22-A114)	V _{esd}	30	00	V
RMS Isolation Voltage (t = 0.3 sec., R.H. \leq 30%, T _A = 25°C) (Figure 15)	V _{ISO}	4500	-	V
Peak Diode Recovery (Note 2)	dV/dt	4.	.5	V/ns
MOSFET dV/dt	dV/dt	6	0	V/ns
Continuous Source Current (Body Diode)	I _S	4.0		Α
Maximum Temperature for Soldering Leads	TL			°C
Operating Junction and Storage Temperature Range	T _J , T _{stg}	-55 t	o 150	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

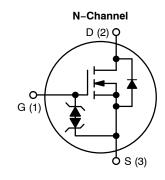
- 1. Limited by maximum junction temperature
- 2. $I_{SD} = 4.0 \text{ A}, \text{ di/dt} \le 100 \text{ A/}\mu\text{s}, V_{DD} \le BV_{DSS}, T_J = +150^{\circ}\text{C}$



ON Semiconductor®

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V _{DSS} (@ T _{Jmax})	R _{DS(on)} (MAX) @ 2 A
650 V	2.0 Ω





NDF04N60ZG, NDF04N60ZH TO-220FP CASE 221AH



NDD04N60Z-1G **IPAK** CASE 369D

1



NDD04N60ZT4G **DPAK** CASE 369AA

ORDERING AND MARKING INFORMATION

See detailed ordering, marking and shipping information on page 6 of this data sheet.

THERMAL RESISTANCE

Parameter		Symbol	Value	Unit
Junction-to-Case (Drain)	NDF04N60Z NDD04N60Z	$R_{ heta JC}$	4.2 1.5	°C/W
Junction-to-Ambient Steady State	(Note 3) NDF04N60Z (Note 4) NDD04N60Z (Note 3) NDD04N60Z-1	$R_{ hetaJA}$	50 38 80	

^{3.} Insertion mounted

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted)

Characteristic	Test Conditions		Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	ı	BV _{DSS}	600			V
Breakdown Voltage Temperature Coefficient	Reference to 25°C, $I_D = 1 \text{ mA}$		$\Delta BV_{DSS}/ \Delta T_{J}$		0.6		V/°C
Drain-to-Source Leakage Current	V _{DS} = 600 V, V _{GS} = 0 V	25°C 150°C	I _{DSS}			1 50	μΑ
Gate-to-Source Forward Leakage	V _{GS} = ±20 V	1	I _{GSS}			±10	μΑ
ON CHARACTERISTICS (Note 5)							
Static Drain-to-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_D = 2.0 \text{ A}$	Ą	R _{DS(on)}		1.8	2.0	Ω
Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 50 \mu$	4	V _{GS(th)}	3.0	3.9	4.5	V
Forward Transconductance	V _{DS} = 15 V, I _D = 2.0 A	4	9FS		3.3		S
YNAMIC CHARACTERISTICS					•	•	•
Input Capacitance (Note 6)	V _{DS} = 25 V, V _{GS} = 0 V, f = 1.0 MHz		C _{iss}	427	535	640	pF
Output Capacitance (Note 6)			C _{oss}	50	62	75	
Reverse Transfer Capacitance (Note 6)			C _{rss}	8	14	20	
Total Gate Charge (Note 6)			Qg	10	19	29	nC
Gate-to-Source Charge (Note 6)	$V_{DD} = 300 \text{ V}, I_D = 4.0 \text{ A}$	۵,	Q _{gs}	2	3.9	6	
Gate-to-Drain ("Miller") Charge	V_{GS} = 10 V		Q_{gd}	5	10	15	nC
Plateau Voltage			V _{GP}		6.5		V
Gate Resistance			R_{g}		4.7		Ω
RESISTIVE SWITCHING CHARACTERI	STICS						
Turn-On Delay Time			t _{d(on)}		13		ns
Rise Time	$V_{DD} = 300 \text{ V}, I_D = 4.0 \text{ A}$	۵,	t _r		9.0		
Turn-Off Delay Time	$V_{GS} = 10 \text{ V}, R_{G} = 5 \Omega$		t _{d(off)}		24		1
Fall Time			t _f		15		1
OURCE-DRAIN DIODE CHARACTER	ISTICS (T _C = 25°C unless oth	erwise not	ed)				
Diode Forward Voltage	I _S = 4.0 A, V _{GS} = 0 V		V _{SD}			1.6	V
Reverse Recovery Time	V _{GS} = 0 V, V _{DD} = 30 V	/	t _{rr}		285		ns
Reverse Recovery Charge	I _S = 4.0 A, di/dt = 100 A		Q _{rr}		1.3		μС

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

5. Pulse Width ≤ 380 μs, Duty Cycle ≤ 2%.

6. Guaranteed by design.

^{4.} Surface mounted on FR4 board using 1" sq. pad size (Cu area = 1.127 in sq [2 oz] including traces).

TYPICAL CHARACTERISTICS

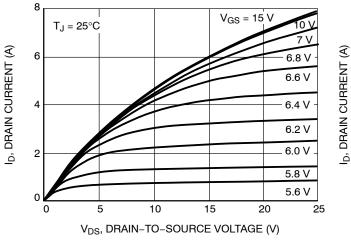
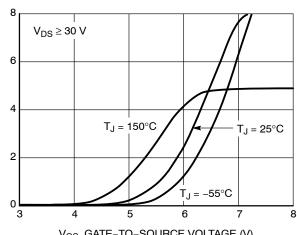


Figure 1. On-Region Characteristics



V_{GS}, GATE-TO-SOURCE VOLTAGE (V) Figure 2. Transfer Characteristics

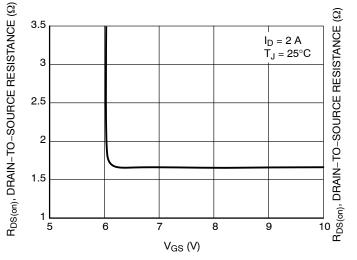


Figure 3. On-Resistance vs. Gate Voltage

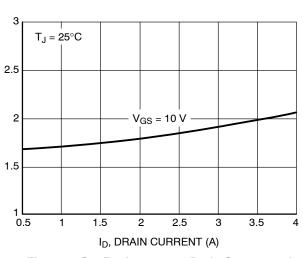


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

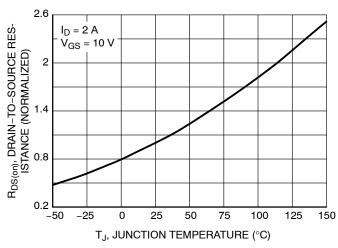


Figure 5. On–Resistance Variation with Temperature

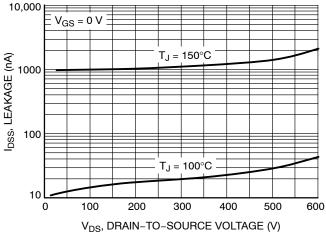
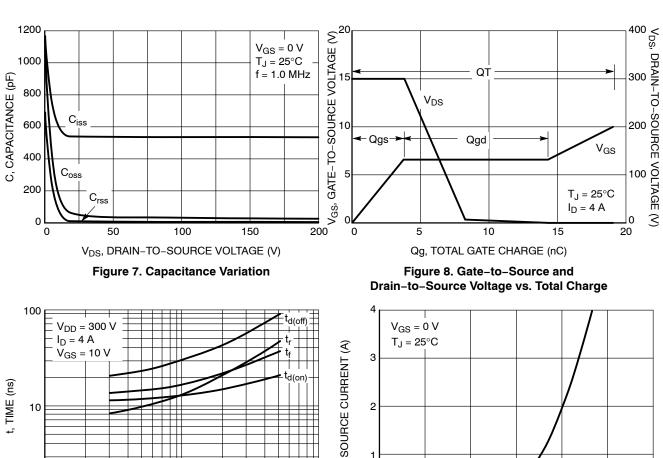


Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS



<u>ŵ</u>

V_{GS} = 10 V t, TIME (ns) 10 10 100 R_G , GATE RESISTANCE (Ω)

Figure 9. Resistive Switching Time Variation vs. Gate Resistance

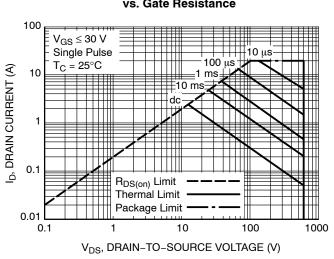


Figure 11. Maximum Rated Forward Biased Safe Operating Area for NDF04N60Z

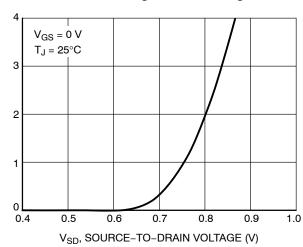


Figure 10. Diode Forward Voltage vs. Current

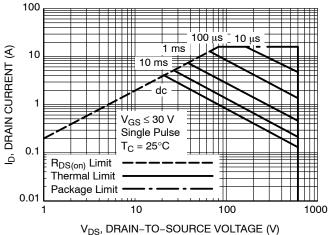


Figure 12. Maximum Rated Forward Biased Safe Operating Area for NDD04N60Z

TYPICAL CHARACTERISTICS

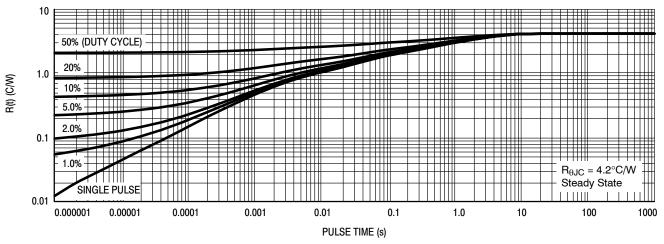


Figure 13. Thermal Impedance for NDF04N60Z

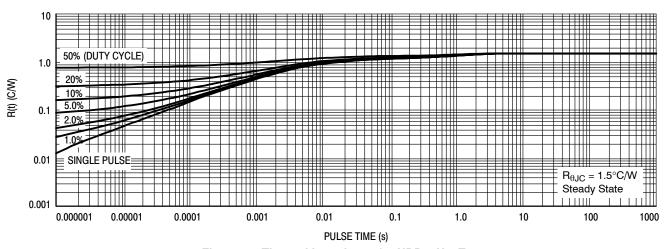


Figure 14. Thermal Impedance for NDD04N60Z

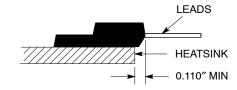


Figure 15. Mounting Position for Isolation Test

Measurement made between leads and heatsink with all leads shorted together.

*For additional mounting information, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

ORDERING INFORMATION

Order Number	Package	Shipping [†]
NDF04N60ZG	TO-220FP (Pb-Free, Halogen-Free)	50 Units / Rail
NDF04N60ZH	TO-220FP (Pb-Free, Halogen-Free)	50 Units / Rail
NDD04N60Z-1G	IPAK (Pb-Free, Halogen-Free)	75 Units / Rail
NDD04N60ZT4G	DPAK (Pb-Free, Halogen-Free)	2500 / Tape and Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

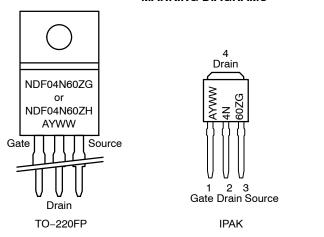
4 Drain

1 Drain 3

DPAK

Gate Source

MARKING DIAGRAMS



A = Location Code*

Y = Year

WW = Work Week

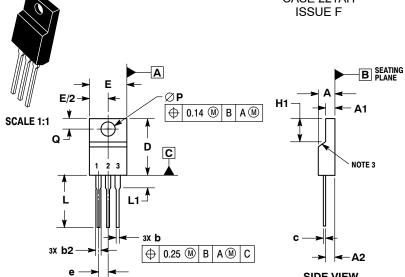
G, H = Pb-Free, Halogen-Free Package

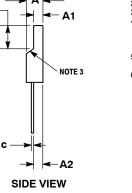
^{*} The Assembly Location Code (A) is front side optional. In cases where the Assembly Location is stamped in the package bottom (molding ejecter pin), the front side assembly code may be blank.



ISSUE F

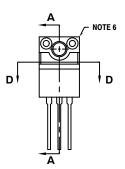
DATE 30 SEP 2014

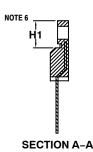






FRONT VIEW





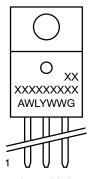
ALTERNATE CONSTRUCTION

NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- 2. CONTROLLING DIMENSION: MILLIMETERS.
 3. CONTOUR UNCONTROLLED IN THIS AREA.
- CONTOUR ONCOUNT HOLLED IN THIS AREA.
 DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH AND GATE PROTRUSIONS. MOLD FLASH AND GATE PROTRUSIONS NOT TO EXCEED 0.13 PER SIDE. THESE DIMENSIONS ARE TO BE MEASURED AT OUTERMOST EXTREME OF THE PLASTIC BODY.
 DIMENSION b2 DOES NOT INCLUDE DAMBAR PROTRUSION.
 LEAD WIDTH INCLUDING PROTRUSION SHALL NOT EXCEED 2.00.
- CONTOURS AND FEATURES OF THE MOLDED PACKAGE BODY MAY VARY WITHIN THE ENVELOP DEFINED BY DIMENSIONS AT AND H1 FOR MANUFACTURING PURPOSES.

	MILLIMETERS			
DIM	MIN	MAX		
Α	4.30	4.70		
A1	2.50	2.90		
A2	2.50	2.90		
b	0.54	0.84		
b2	1.10	1.40		
С	0.49	0.79		
D	14.70	15.30		
E	9.70	10.30		
е	2.54	BSC		
H1	6.60	7.10		
L	12.50	14.73		
L1		2.80		
P	3.00	3.40		
Q	2.80	3.20		

GENERIC MARKING DIAGRAM*



= Assembly Location

WL = Wafer Lot

= Year

WW = Work Week

G = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ■", may or may not be present.

STYLE 1:		STYLE 2:	
PIN 1.	MAIN TERMINAL 1	PIN 1.	CATHODE
2.	MAIN TERMINAL 2	2.	ANODE
3.	GATE	3.	GATE

DOCUMENT NUMBER:	98AON52577E	Electronic versions are uncontrolled except when accessed directly from the Document Reportant versions are uncontrolled except when stamped "CONTROLLED COPY" in red.	
DESCRIPTION:	TO-220 FULLPACK, 3-LEA	AD	PAGE 1 OF 1

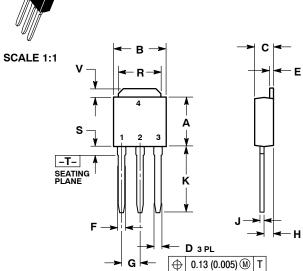
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MECHANICAL CASE OUTLINE





DATE 15 DEC 2010



STYLE 2:

PIN 1. GATE

3

STYLE 6: PIN 1. MT1 2. MT2 3. GATE

2. DRAIN

4. DRAIN

MT2

SOURCE

STYLE 1: PIN 1. BASE

3

STYLE 5: PIN 1. GATE

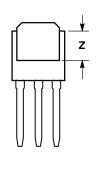
2. ANODE 3. CATHODE

ANODE

2. COLLECTOR

EMITTER

COLLECTOR



NOTES:

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 2. CONTROLLING DIMENSION: INCH.

	INC	HES	MILLIN	ETERS
DIM	MIN	MAX	MIN	MAX
Α	0.235	0.245	5.97	6.35
В	0.250	0.265	6.35	6.73
С	0.086	0.094	2.19	2.38
D	0.027	0.035	0.69	0.88
E	0.018	0.023	0.46	0.58
F	0.037	0.045	0.94	1.14
G	0.090	BSC	2.29	BSC
Н	0.034	0.040	0.87	1.01
J	0.018	0.023	0.46	0.58
K	0.350	0.380	8.89	9.65
R	0.180	0.215	4.45	5.45
S	0.025	0.040	0.63	1.01
٧	0.035	0.050	0.89	1.27
Z	0.155		3.93	

MARKING DIAGRAMS

STYLE 3: PIN 1. ANODE

2. CATHODE

4. CATHODE

3 ANODE

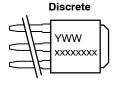
STYLE 7: PIN 1. GATE 2. COLLECTOR

3. EMITTER

COLLECTOR

STYLE 4: PIN 1. CATHODE ANODE
 GATE

4. ANODE

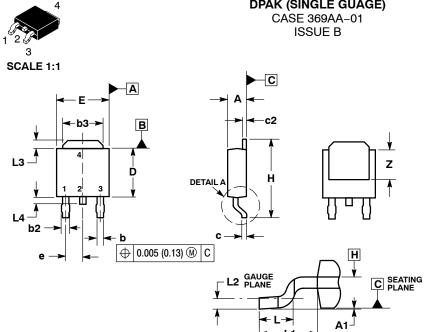




xxxxxxxxx = Device Code Α = Assembly Location IL = Wafer Lot Υ = Year WW = Work Week

DOCUMENT NUMBER:	98AON10528D	Electronic versions are uncontrolled except when accessed directly from Printed versions are uncontrolled except when stamped "CONTROLLED	
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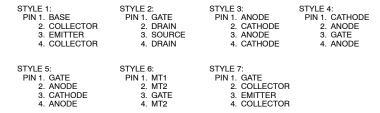


DETAIL A ROTATED 90° CW **DATE 03 JUN 2010**

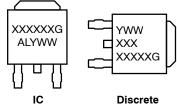
NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- 2. CONTROLLING DIMENSION: INCHES.
 3. THERMAL PAD CONTOUR OPTIONAL WITHIN DI-MENSIONS b3, L3 and Z.
 4. DIMENSIONS D AND E DO NOT INCLUDE MOLD
- FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.006 INCHES PER SIDE
- DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 6. DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.

	INC	HES	MILLIN	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.086	0.094	2.18	2.38
A1	0.000	0.005	0.00	0.13
b	0.025	0.035	0.63	0.89
b2	0.030	0.045	0.76	1.14
b3	0.180	0.215	4.57	5.46
С	0.018	0.024	0.46	0.61
c2	0.018	0.024	0.46	0.61
D	0.235	0.245	5.97	6.22
E	0.250	0.265	6.35	6.73
е	0.090	BSC	2.29 BSC	
Н	0.370	0.410	9.40	10.41
L	0.055	0.070	1.40	1.78
L1	0.108	REF	2.74	REF
L2	0.020 BSC		0.51	BSC
L3	0.035	0.050	0.89	1.27
L4		0.040		1.01
Z	0.155		3.93	



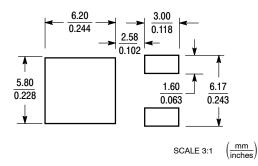
GENERIC MARKING DIAGRAM*



XXXXXX = Device Code Α = Assembly Location L = Wafer Lot ٧ = Year = Work Week WW = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking.

SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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